Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	ent under	
09/886,064	HAITSMA ET AL.		
Examiner	Art Unit		
Shin-Hon Chen	2131		

SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, PGPUB, EPO, JPO, DERWENT (BRS Search)	7/12/2006	S.C.		